Application/Control No. O9/767,730 Examiner Tan Dean D. Nguyen Applicant(s)/Patent Under Reexamination BUCKLEY ET AL. Art Unit Page 1 of 1 U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2001/0032092	10-2001	Calver, James	705/1
	В	US-			
	С	US-			
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